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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/567,070	02/03/2006	Michiel Jos Van Duuren	NL03 0977 US1 9477	
	7590 03/08/200 CTRONICS NORTH A	EXAMINER		
INTELLECTUA	AL PROPERTY & ST	LAPPAS, JASON		
SAN JOSE, CA	DRIVE, M/S-41SJ \$ 95131		ART UNIT	PAPER NUMBER
, , , , ,		2827		
SHORTENED STATUTOR	Y PERIOD OF RESPONSE	MAIL DATE	DELIVERY MODE	
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Please find below and/or attached an Office communication concerning this application or proceeding.

If NO period for reply is specified above, the maximum statutory period will apply and will expire 6 MONTHS from the mailing date of this communication.

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		Applicati	on No.	Applicant(s)	_
		10/567,0	70	VAN DUUREN, MICHIEL JOS	
	Office Action Summary	Examine	•	Art Unit	_
		Jason La	pas	2827	
Period fo	The MAILING DATE of this communi or Reply	cation appears on the	e cover sheet with the c	orrespondence address	
WHIC - Exter after - If NO - Failu Any	CRTENED STATUTORY PERIOD FOR HEVER IS LONGER, FROM THE MASSICE OF	AILING DATE OF TH of 37 CFR 1.136(a). In no ev unication., tutory period will apply and w will, by statute, cause the app	HIS COMMUNICATION ent, however, may a reply be timil expire SIX (6) MONTHS from lication to become ABANDONE	N. nely filed the mailing date of this communication. D (35 U.S.C. § 133).	
Status					
1)⊠	Responsive to communication(s) file	d on 03 February 20	06.		
• —	•	2b)⊠ This action is r			
·—	Since this application is in condition	<i>,</i> —		secution as to the merits is	
/—	closed in accordance with the practic	•	·		
Dispositi	on of Claims				
4) 🖂	Claim(s) 1-14 is/are pending in the a	pplication.	•		
•	4a) Of the above claim(s) is/ai		nsideration.	•	
	Claim(s) is/are allowed.				
6)🖂	Claim(s) 1-14 is/are rejected.	•			
7)	Claim(s) is/are objected to.				
8)[Claim(s) are subject to restric	tion and/or election i	equirement.	,	
Applicati	on Papers				
9)[7]	The specification is objected to by the	e Examiner.			
,	The drawing(s) filed on <u>03 February</u>		cepted or b) Objecte	d to by the Examiner.	
,—	Applicant may not request that any object				
	Replacement drawing sheet(s) including				
11)	The oath or declaration is objected to	by the Examiner. N	ote the attached Office	Action or form PTO-152.	
Priority (under 35 U.S.C. § 119				
•	Acknowledgment is made of a claim ☐ All b)☐ Some * c)☐ None of:	for foreign priority ur	der 35 U.S.C. § 119(a)-(d) or (f).	
,	1.⊠ Certified copies of the priority	documents have bee	en received.	•	
•	2. Certified copies of the priority	documents have been	en received in Applicat	ion No	
	3. Copies of the certified copies	of the priority docum	ents have been receive	ed in this National Stage	
	application from the Internatio	nal Bureau (PCT Ru	le 17.2(a)).	•	
* 5	See the attached detailed Office actio	n for a list of the cert	ified copies not receive	ed.	
		•			
Attachmen	it(s)				
_	ce of References Cited (PTO-892)		4) Interview Summary		
	ce of Draftsperson's Patent Drawing Review (P	PTO-948)	Paper No(s)/Mail D 5) Notice of Informal F		
	mation Disclosure Statement(s) (PTO/SB/08) er No(s)/Mail Date <u>2/3/2006</u> .	•	6) Other:		

DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 1. Claims 1-2, 5-6, 14 are rejected under 35 U.S.C. 102(b) as being anticipated by Shiga (U.S. Patent 6,778,443).
- Claim 1. Shiga teaches a method for operating an array of non-volatile (Shiga, Title) charge trapping memory devices (Shiga teaches flash memory cells which are charge trapping memory devices), comprising:
- before a block erase step of substantially all of the non-volatile memory devices of the array, block programming of substantially all (after ease execution is confirmed the first block is pre-programmed and subsequently undergoes data erase, steps repeat for proceeding blocks. Shiga Col 1 lines 33-34. When all blocks are selected all blocks are preprogrammed then erased. Examiner would like to point out that substantially all is not exactly all.) of the non-volatile memory devices of the array (Nonvolatile Shiga, Title).

Claim 2. Shiga teaches a method according to claim 1, furthermore comprising after the erase operation, programming some of the non-volatile memory devices of the array (after erase execution is confirmed, the first block is preprogrammed, Shiga Col 1 lines 33-35), depending on data content to be stored in the non-volatile memory devices of the array (erase is undergone only to blocks that need it, Shiga Col 1 43-46).

Claim 5. Shiga teaches an electrical device comprising an array of non-volatile charge trapping memory devices (Shiga, Title), comprising: means for block programming of substantially all of the non-volatile memory devices of the array (after ease execution is confirmed the first block is pre-programmed and subsequently undergoes data erase, steps repeat for proceeding blocks. Shiga Col 1 lines 33-34. When all blocks are selected all blocks are preprogrammed then erased.), means for block erasing of substantially all of the programmed non- volatile memory devices of the array (erase occurs after preprogram Col 1 lines 32-34), - control means for controlling the array of non-volatile memory devices such that before block erasing of substantially all of the non-volatile memory devices of the array, substantially all of the non-volatile memory devices of the array are block programmed (means for controlling the array for preprogramming is the process check Col 1 lines 43-47).

Claim 6. An electrical device according to claim 5, wherein the non-volatile memory device comprises a transistor having a channel and a control gate, a dielectric charge

trapping layer being located between the channel and the control gate (this is an inherent structure of a memory cell in the memory array).

Claim 14. An electrical device according to claim 5, wherein the array of non-volatile memory devices forms a non-volatile memory (this is an inherent structure of a non-volatile memory array).

Claim Rejections - 35 USC § 103

- 2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 3. Claim 3-4 rejected under 35 U.S.C. 103(a) as being unpatentable over Shiga (U.S. Patent 6,778,443), in view of Yamazoe (U.S. Patent 7,009,890).
- Claim 3. Shiga teaches a method according to claim 2, furthermore comprising reading the data content stored in a non-volatile memory device of the array (reading verification Col 9 lines 7-10).

It is noted that Shiga is silent with respect for reading the data content stored in a non-volatile memory device of the array at least one further non-volatile memory device having a dielectric charge trapping layer is used as reference cell which is programmed

and erased for a block programming and block erase, respectively, of the non-volatile memory devices in the array.

However Yamazoe teaches reference memory allocated in a unit of a block to be erased or programming to control the timing for a plurality of memories using information from the reference cell (Yamazoe Col 7 lines 3-6). Charge trapping layers are inherent in memory cells. Read timing is based on the deterioration of the reference memory (Col 7 lines 11-13).

It would have been obvious to one of ordinary skill in the art at the time the invention was made to use the reference cells taught be Yamazoe in the circuit taught be Shiga to control the timing of a plurality of memories based on the deterioration of the reference cell.

Claim 4. Method according to claim 3, wherein the memory devices of the array together function as reference cells (Yamazoe teaches reference cells in the memory array since they are coupled to the same bitline decoder and are part of the same block. These are normal cells, memory devices, which function as reference cells, Yamazoe Fig 8).

- 4. Claim 7 is rejected under 35 U.S.C. 103(a) as being unpatentable over Shiga (U.S. Patent 6,778,443), in view of Hirakawa (U.S. Patent 2001/0007541)
- Claim 7. Shiga teaches an electrical device according to claim 5.

It is noted that Shiga is silent with respect to the array being provided with at least one non-volatile memory device for use as a reference cell in a sense amplifier.

However Hirakawa teaches a reference cell in a sense amp. The reference cell may be part of the array or separate from the array (applicants spec page 5 lines 29-33). Having the reference cell the sense amp as opposed to the memory array is merely a rearrangement of parts.

It would have been obvious to one of ordinary skill in the art at the time the invention was made to have the reference cell in the sense amp since it has been held that rearranging parts of an invention involves only routine skill in the art. *In re Japikse*, 86 USPQ 70

- 5. Claims 8-13 are rejected under 35 U.S.C. 103(a) as being unpatentable over Shiga (U.S. Patent 6,778,443), in view of Hirakawa (U.S. Patent 2001/0007541) further in view of Yamazoe (U.S. Patent 7,009,890).
- Claim 8. Shiga and Hirakawa teach an electrical device according to claim 7.

It is noted that they are silent with respect to the array comprising means for programming and erasing the reference cell for a block-programming and block-erasing respectively of the non-volatile memory devices in the array.

However Yamazoe teaches reference memory allocated in a unit of a block to be erased or programming to control the timing for a plurality of memories using

information from the reference cell (Yamazoe Col 7 lines 3-6). Read timing is based on the deterioration of the reference memory (Col 7 lines 11-13).

It would have been obvious to one of ordinary skill in the art at the time the invention was made to use the reference cells taught be Yamazoe in the circuit taught be Shiga to control the timing of a plurality of memories based on the deterioration of the reference cell.

Claim 9. An electrical device according to claim 7, wherein the at least one reference cell is separate from the array (claim 7 addresses a reference cell in a sense amp which is separate from the array).

Claim 10. An electrical device according to claim 7, wherein the memory devices of the array together function as reference cells (reference cells found in the memory block, Shiga Fig 8).

Claim 11. An electrical device according to claim 7, comprising means for comparing a read current from a non-volatile memory device in the array with a read current from the reference cell (reading method using a sense amplifier, Yamazoe Col 5 lines 44-49. reference cells are addressed to be found in array. Use of a reference cell in a sense amp outside the array is addressed above in claim 7).

Claim 12. An electrical device according to claim 7, comprising means for adapting a read current for reading the non-volatile memory devices in the array (the sense amplifier is a mean for adapting current for reading, addressed in claim 11, Yamazoe Col 5 lines 44-49. Adapting a current when sense amp is reading is an inherent property of a sense amp) to the aging of the reference cell (reading time is based on deterioration of the reference memory, Yamazoe Col 7 lines 11-13).

Claim 13. An electrical device according to claim 7, comprising means for adapting a required control gate voltage (sense amp outputs a wait signal, which controls the read timing depending on the degree of deterioration on the memory, Yamazoe Col 7 lines 21-27, 34-36) for reading the non-volatile memory devices in the array (adapting a read current is addressed in claim 12. Voltage is inherently adapted when current is), depending on the aging of the reference cell (time is based on deterioration of the reference memory, Col 7 lines 11-13).

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Jason Lappas whose telephone number is (571)270-1272. The examiner can normally be reached on M-F 7:30AM-5:00PM EST.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Amir Zarabian can be reached on (571) 272-1852. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/567,070

Art Unit: 2827

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

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